# MOSFET - Power, Single, N-Channel, Logic Level, SOT-23

60 V, 155 m $\Omega$ 

#### **Features**

- Small Footprint Industry Standard Surface Mount SOT-23 Package
- Low R<sub>DS(on)</sub> for Low Conduction Losses and Improved Efficiency
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

#### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Param	Symbol	Value	Unit		
Drain-to-Source Voltage	V <sub>DSS</sub>	60	V		
Gate-to-Source Voltage			V <sub>GS</sub>	±20	V
Continuous Drain	Steady State	T <sub>A</sub> = 25°C	I <sub>D</sub>	2.2	Α
Current R <sub>ΨJ-mb</sub> (Notes 1, 2, 3, and 4)	State	T <sub>A</sub> = 100°C		1.6	
Power Dissipation		T <sub>A</sub> = 25°C	P <sub>D</sub>	1.5	W
R <sub>ΨJ-mb</sub> (Notes 1 and 3)		T <sub>A</sub> = 100°C		0.6	
Continuous Drain	Steady State	T <sub>A</sub> = 25°C	I <sub>D</sub>	1.7	Α
Current R <sub>0JA</sub> (Note 1, 2, 3, and 4)	State	T <sub>A</sub> = 100°C		1.2	
Power Dissipation R <sub>θJA</sub>		T <sub>A</sub> = 25°C	P <sub>D</sub>	0.9	W
(Notes 1 and 3)		T <sub>A</sub> = 100°C		0.4	
Pulsed Drain Current	, , ,	= 25°C, = 10 μs	I <sub>DM</sub>	27	Α
Operating Junction and S	T <sub>J</sub> , T <sub>stg</sub>	–55 to 150	°C		
Source Current (Body Die	Is	1.9	Α		
Lead Temperature for So (1/8" from case for 10 s)	TL	260	°C		

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Psi  $(\Psi)$  is used as required per JESD51-12 for packages in which substantially less than 100% of the heat flows to single case surface.
- 3. Surface-mounted on FR4 board using a 650 mm2, 2 oz. Cu pad.
- Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

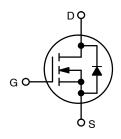


# ON Semiconductor®

#### www.onsemi.com

V <sub>(BR)DSS</sub>	V <sub>(BR)DSS</sub> R <sub>DS(on)</sub> TYP		
60 V	155 mΩ @ 10 V	2.2 A	
	205 mΩ @ 4.5 V	2.27	

#### N-Channel





SOT-23 CASE 318 STYLE 21





AA6 = Device Code

M = Date Code\*

Pb-Free Package

(Note: Microdot may be in either location)

\*Date Code orientation may vary depending upon manufacturing location.

### ORDERING INFORMATION

Device	Package	Shipping <sup>†</sup>
NTR5198NLT1G	SOT-23 (Pb-Free)	3000 / Tape & Reel
NTR5198NLT3G	SOT-23 (Pb-Free)	10000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

#### THERMAL RESISTANCE RATINGS

Parameter	Symbol	Max	Unit
Junction-to-Lead #3 - Drain (Notes 2 and 3)		86	°C/W
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	139	°C/W

#### **ELECTRICAL CHARACTERISTICS** (T<sub>1</sub> = 25°C unless otherwise noted)

Parameter	Symbol	Test Conditions		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA		60			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /T <sub>J</sub>	Reference to 25°C, $I_D = 250 \mu A$			70		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 60 V	T <sub>J</sub> = 25°C			1.0	μΑ
			T <sub>J</sub> = 125°C			10	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, \	/ <sub>GS</sub> = ±20 V			±100	nA
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	V <sub>GS</sub> = V <sub>DS</sub> ,	I <sub>D</sub> = 250 μA	1.5		2.5	V
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>	Reference to 25	5°C, I <sub>D</sub> = 250 μA		-6.5		mV/°C
Drain-to-Source On-Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10	V, I <sub>D</sub> = 1 A		107	155	mΩ
		V <sub>GS</sub> = 4.5	V, I <sub>D</sub> = 1 A		142	205	
Forward Transconductance	9FS	V <sub>DS</sub> = 5.0	V, I <sub>D</sub> = 1 A		3		S
CHARGES, CAPACITANCES & GATE	RESISTANCE						
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 \text{ V, f} = 1.0 \text{ MHz,}$ $V_{DS} = 25 \text{ V}$			182		pF
Output Capacitance	C <sub>oss</sub>				25		
Reverse Transfer Capacitance	C <sub>rss</sub>				16		
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>DS</sub> = 48 V,	V <sub>GS</sub> = 4.5 V		2.8		nC
	=.(. = .)	$I_D = 1 A$	V <sub>GS</sub> = 10 V		5.1		
Threshold Gate Charge	Q <sub>G(TH)</sub>		•		0.3		
Gate-to-Source Charge	Q <sub>GS</sub>	Vne = 48	V, I <sub>D</sub> = 1 A		0.8		
Gate-to-Drain Charge	$Q_{GD}$	V <sub>GS</sub> =	= 10 V		1.5		
Plateau Voltage	$V_{GP}$				3.1		V
Gate Resistance	$R_{G}$				8		Ω
SWITCHING CHARACTERISTICS (No	ote 6)			•	-		-
Turn-On Delay Time	t <sub>d(on)</sub>				5		ns
Rise Time	t <sub>r</sub>	Vne = 30 V.	V <sub>GS</sub> = 10 V.		7		
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{DS} = 30 \text{ V}, V_{GS} = 10 \text{ V},$ $I_{D} = 1 \text{ A}, R_{G} = 10 \Omega$			13		
Fall Time	t <sub>f</sub>				2		
DRAIN-SOURCE DIODE CHARACTE	RISTICS						
Forward Diode Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 1 A	T <sub>J</sub> = 25°C		0.8	1.2	V
			T <sub>J</sub> = 125°C		0.6		
Reverse Recovery Time	t <sub>rr</sub>	I			12		ns
Charge Time	ta	$\begin{split} I_S = 1 \; A_{dc},  V_{GS} = 0 \; V_{dc}, \\ dI_S/dt = 100 \; A/\mu s \end{split} \label{eq:interpolation}$			9		
Discharge Time	t <sub>b</sub>				3		
Reverse Recovery Stored Charge	Q <sub>RR</sub>				6		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 5. Pulse Test: Pulse Width  $\leq$  300  $\mu$ s, Duty Cycle  $\leq$  2%.

<sup>6.</sup> Switching characteristics are independent of operating junction temperatures.

### **TYPICAL CHARACTERISTICS**

ID, DRAIN CURRENT (A)

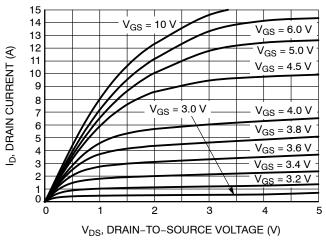


Figure 1. On-Region Characteristics

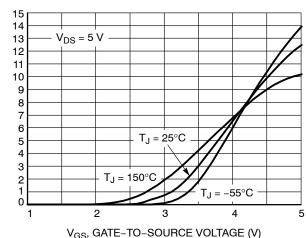


Figure 2. Transfer Characteristics

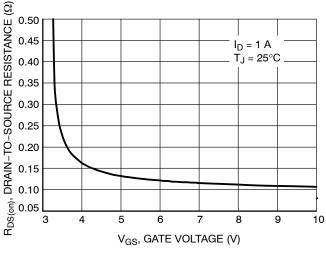


Figure 3. On-Resistance vs. Gate-to-Source Voltage

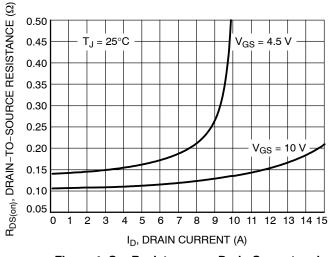
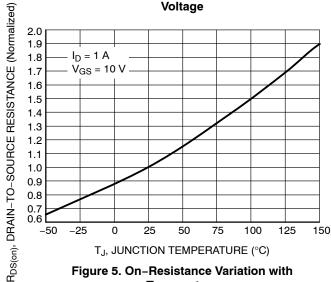


Figure 4. On-Resistance vs. Drain Current and **Gate Voltage** 



**Temperature** 

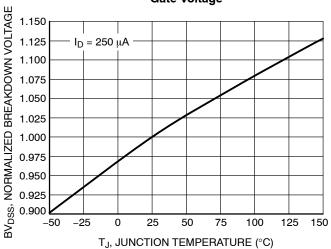


Figure 6. Breakdown Voltage Variation with **Temperature** 

#### TYPICAL CHARACTERISTICS

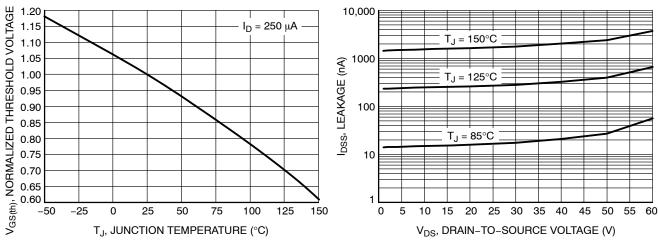


Figure 7. Threshold Voltage Variation with Temperature

Figure 8. Drain-to-Source Leakage Current vs. Voltage

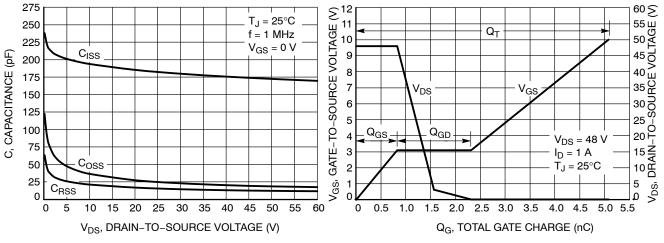


Figure 9. Capacitance Variation

Figure 10. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

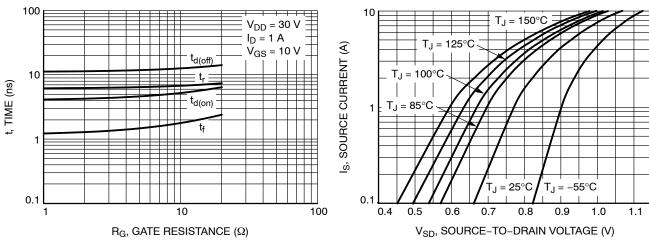


Figure 11. Resistive Switching Time Variation vs. Gate Resistance

Figure 12. Diode Forward Voltage vs. Current

# **TYPICAL CHARACTERISTICS**

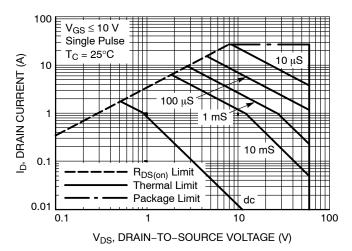


Figure 13. Maximum Rated Forward Biased Safe Operating Area

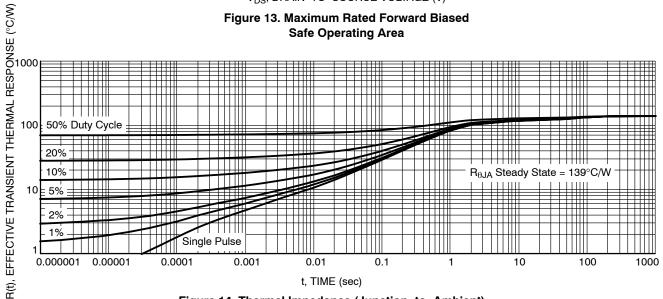
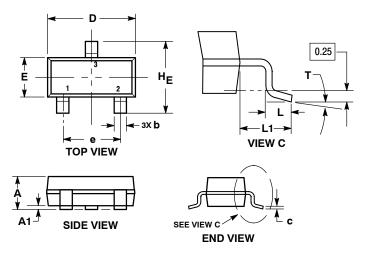


Figure 14. Thermal Impedance (Junction-to-Ambient)

#### PACKAGE DIMENSIONS

SOT-23 (TO-236) CASE 318-08 **ISSUE AR** 



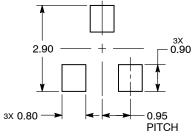
- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
  CONTROLLING DIMENSION: MILLIMETERS.
  MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH.
  MINIMUM LEAD THICKNESS IS THE MINIMUM THICKNESS OF THE BASE MATERIAL.
  DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH,
- PROTRUSIONS, OR GATE BURRS.

	MILLIMETERS			INCHES			
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.89	1.00	1.11	0.035	0.039	0.044	
A1	0.01	0.06	0.10	0.000	0.002	0.004	
b	0.37	0.44	0.50	0.015	0.017	0.020	
С	0.08	0.14	0.20	0.003	0.006	0.008	
D	2.80	2.90	3.04	0.110	0.114	0.120	
E	1.20	1.30	1.40	0.047	0.051	0.055	
е	1.78	1.90	2.04	0.070	0.075	0.080	
L	0.30	0.43	0.55	0.012	0.017	0.022	
L1	0.35	0.54	0.69	0.014	0.021	0.027	
HE	2.10	2.40	2.64	0.083	0.094	0.104	
Т	0°		10 °	0 °		10 °	

#### STYLE 21:

- PIN 1. GATE
  - 2. SOURCE
  - DRAIN

#### RECOMMENDED **SOLDERING FOOTPRINT\***



**DIMENSIONS: MILLIMETERS** 

\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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